CONTRIBUTION TO IXS SECTION (5 MIN)

High spectral density of XFELO:

- allows for x-ray spectrograph with energy resolution of ~0.1 meV and scanning energy range ±1000 meV.
- This will allow to measure <u>complete</u> and <u>exact</u> DOS (density of phonon states).
- Exact DOS may describe lattice dynamics better than dispersive relations.
- Exact DOS may describe structure better than x-ray diffraction

Aleksandr Chumakov, ESRF

NEW SCIENCE WITH ×10³ HIGHER SPECTRAL DENSITY

High spectral density of XFELO:

- allows for high statistical accuracy even if we use much smaller (~0.1 meV) energy bandwidth
- what we need is an x-ray spectrograph with energy resolution of ~0.1 meV and scanning energy range ±1000 meV.
- then we may measure <u>complete</u> and <u>exact</u> DOS

WE ALREADY ALMOST HAVE A SUCH SPECTROGRAPH



Our (ID18, ESRF) standard in-line 0.5 meV monochromator works as a spectrograph:



ESRF

The European Synchrotron

EXACT DOS MAY DESCRIBE LATTICE DYNAMICS BETTER THAN DISPERSION RELATIONS

dispersion relations:

DOS:



J. Neuhaus et al, PRB 89 (2014) 184302



To apply Born-von-Karman fit to DOS



Atomic structure of guanidium nitroprusside:



ESRF

The European Synchrotron

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